## Search Notes



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Reexamination KAPOOR, AJAY

Applicant(s)/Patent Under

Examiner

O'Neill, Patrick

Art Unit

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## SEARCHED

Class	Subclass	Date	Examiner
327	416, 419, 427, 434-437	06/22/07	PO
327	318, 319, 333, 379, 382-384, 387-389, 391	10/5/07	PO

## **SEARCH NOTES**

Search Notes	Date	Examiner	
EAST (all databases)	06/22/07	PO	
IEEE Xplore	06/22/07	PO	
Google	06/22/07	PO	
Inventor Search	06/22/07	PO	
Consulted with Linh Nguyen (Primary)	06/22/07	PO	
Updated EAST (all databases) search	10/5/07	PO	
Consulted with Tuan Lam (Primary)	10/5/07	PO	

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1	Class	Subclass	Date	Examiner
	All	USPGPUB text search	10/5/07	PO,

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